

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination LEE ET AL.	
		Examiner Nhan T. Tran	Art Unit 2622	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0192220	09-2004	Huang et al.	455/556.1
*	B	US-2004/0075620	04-2004	Tanaka et al.	348/207.99
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

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